

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, **Assemblies, Related Materials and Processes**

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity **Approved Process**

IECQ Certificate No.: IECQ-P ULTW 16.0003-07

CB Certificate No.: T1027-7

Schedule Number: IECQ-P ULTW 16.0003-07-S Rev No.: 1 **Revision Date: 2018/09/20** Page 1 of 1

Appendix-1 (T1107-7) Schedule of Scope to Certificate of Approval

Description test	Standard	Remarks
SEM	T-SEM-3	By customer requirement
TEM-EELS	Т-ТЕМ-3	By customer requirement
FIB	T-FIB-3	By customer requirement
Optical Microscope	T-OMI-3	By customer requirement
IC Layout Imaging	T-OMI-3	By customer requirement
Decapsulation	T-LAB-3	By customer requirement
Chemical	T-LAB-3	By customer requirement
Delayer	T-LAB-3	By customer requirement

Technical Reviewer of DQS: Michael Chan Date: Sep. 6, 2018

US-NAI, ECCC T.R.C.C. sign:

Date: Sep. 10, 2018



